

**Oscilloscope**

Osc. Active

Channel 1

Manual

Save

Button is clicked to activate oscilloscope or show graph at memory

To catch the last signal automaticly

**Synchronous**

Channel 1

Up

**1. Channel**

Probe X1

Top Value : 2,98 V

Low Value : -0,02 V

Point :

Frequen. : 1,6 KHz

Position of probe's switch: X 1 or X 10

Ch.1 Input signal values

**2. Channel**

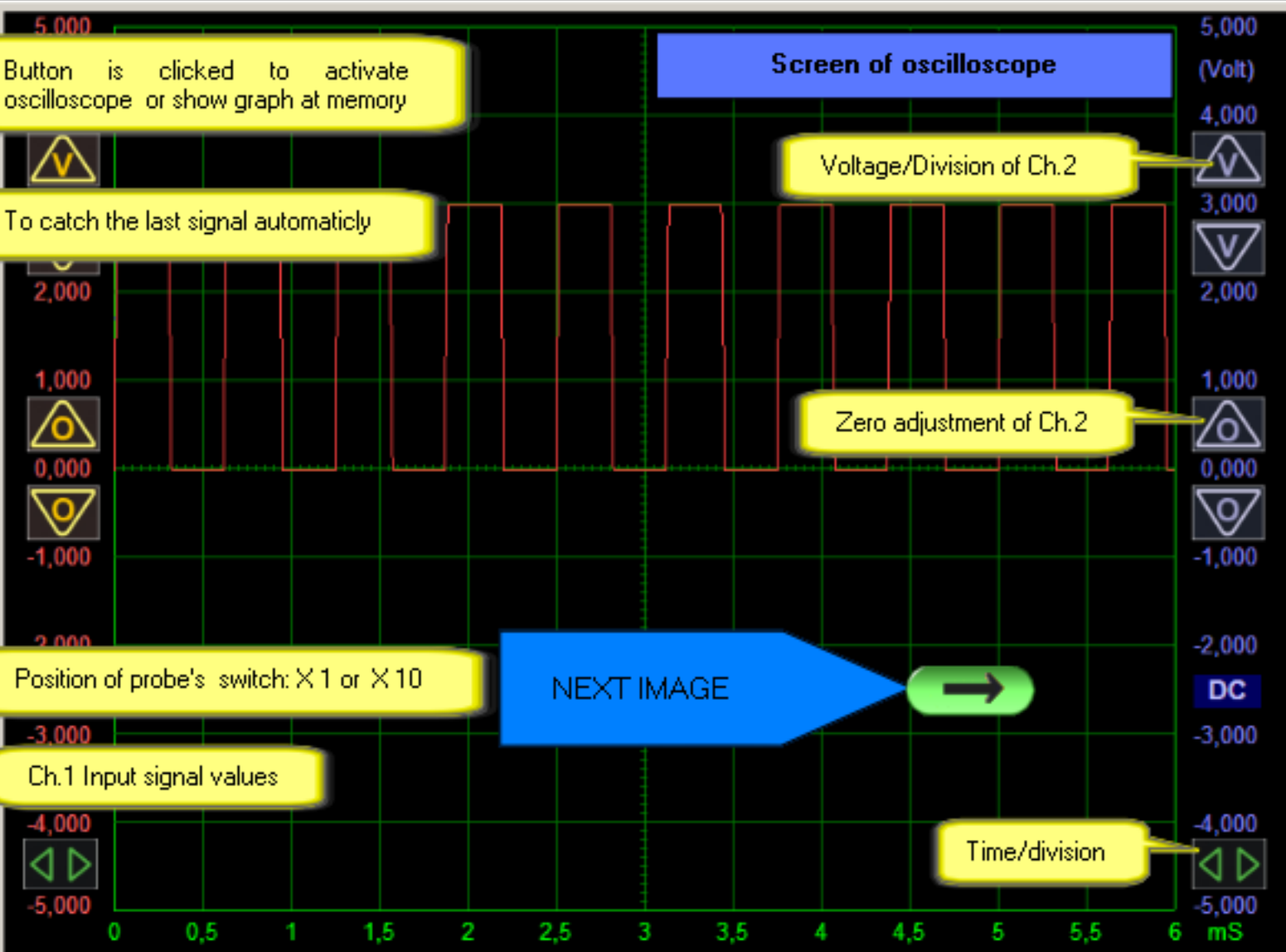
Probe X1

Top Value : 0,00 V

Low Value : 0,00 V

Point :

Frequen. :



ATTENTION: Chassis to connect to the point must be isolated or grounded. ADVICE: Use Probe is 10X position.

**Analog Output (Channel 2)**

Active

Ch.2 activates output signal

Frequency : 1600

Voltage mV: 3000

**Design**

Signal

DAC



Test:

**Channel 1 - 2**

Automatic

1 V  
2 V  
5 V  
10 V

Very Low Frk.  
Low 2 Frk.  
Lov 1 Frk.  
Test Frk.  
H Frk (5-10V)

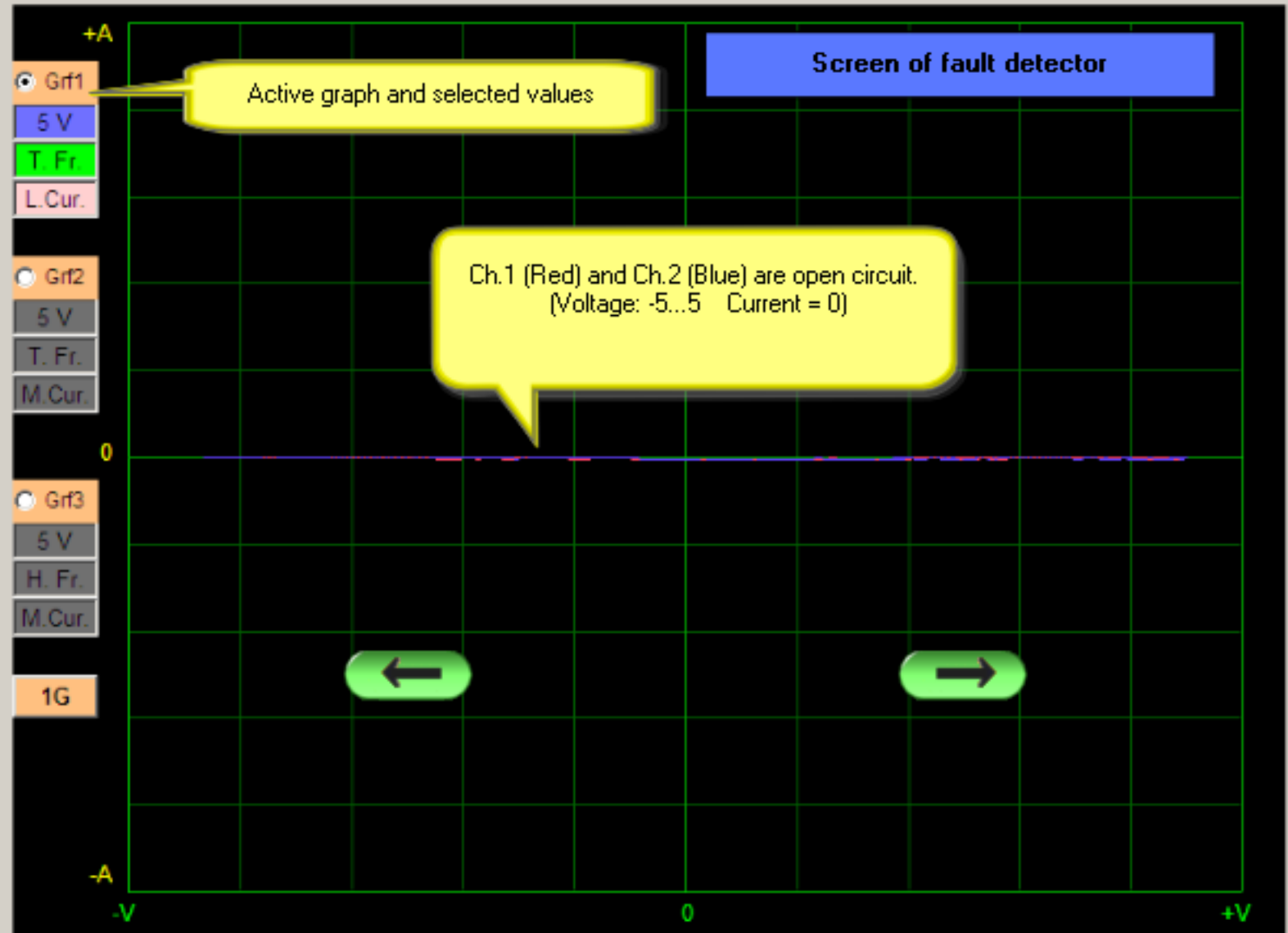
L. Current (47K)  
M. Current (2K7)  
H. Current (550)

Compare  
 Capasite Test  
 T.T.T. FET IGBT

Memory Save - Test

**Recording**

Tolerance (%)



ATTENTION: Probe must be at 1X position. High-voltage capacitors must be emptied by using a resistor.

Reference: Ch1 —

Open Circuit

Test: Ch2 —

Open Circuit

Click to display fault detector screen

Test:

**Channel 1 - 2**

Automatic

1 V  
2 V  
5 V  
10 V

Very Low Frk.  
Low 2 Frk.  
Lov 1 Frk.  
Test Frk.  
H Frk (5-10V)

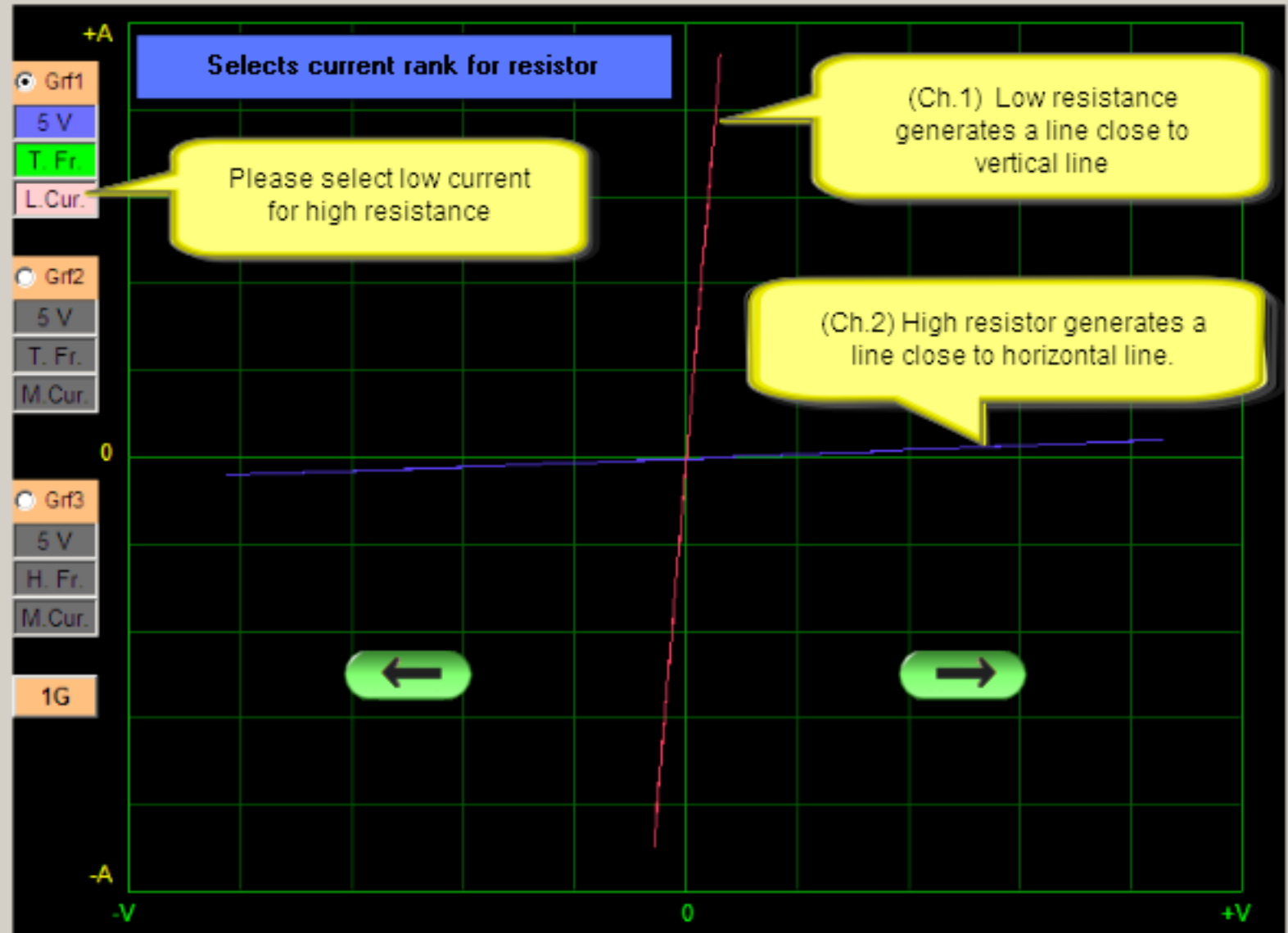
L. Current (47K)  
M. Current (2K7)  
H. Current (550)

Compare  
 Capasite Test  
 T.T.T. FET IGBT

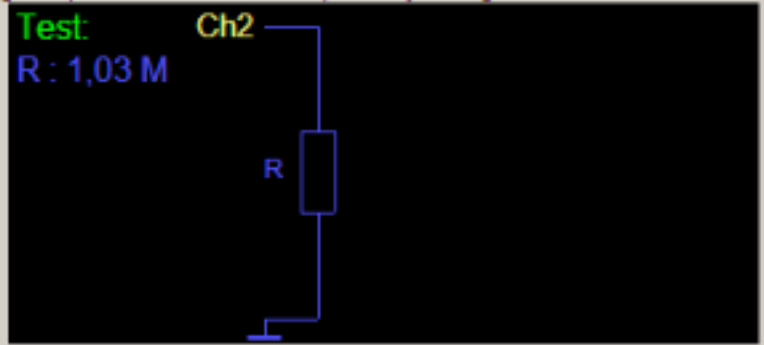
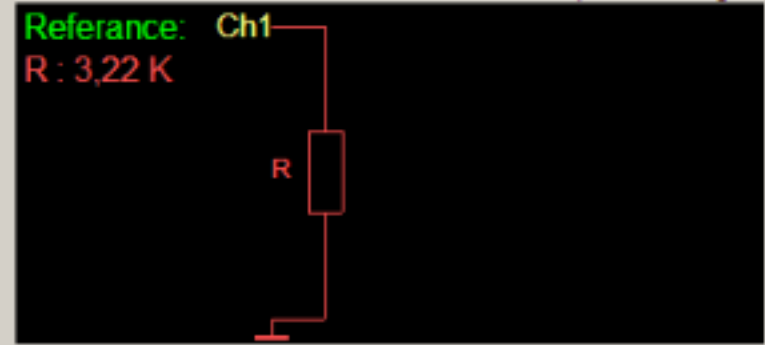
Memory Save - Test

**Recording**

Tolerance (%) **3**



ATTENTION: Probe must be at 1X position. High-voltage capacitors must be emptied by using a resistor.



Test:

**Channel 1 - 2**

Automatic

1 V  
2 V  
5 V  
10 V

Very Low Frk.  
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Test Frk.  
H Frk (5-10V)

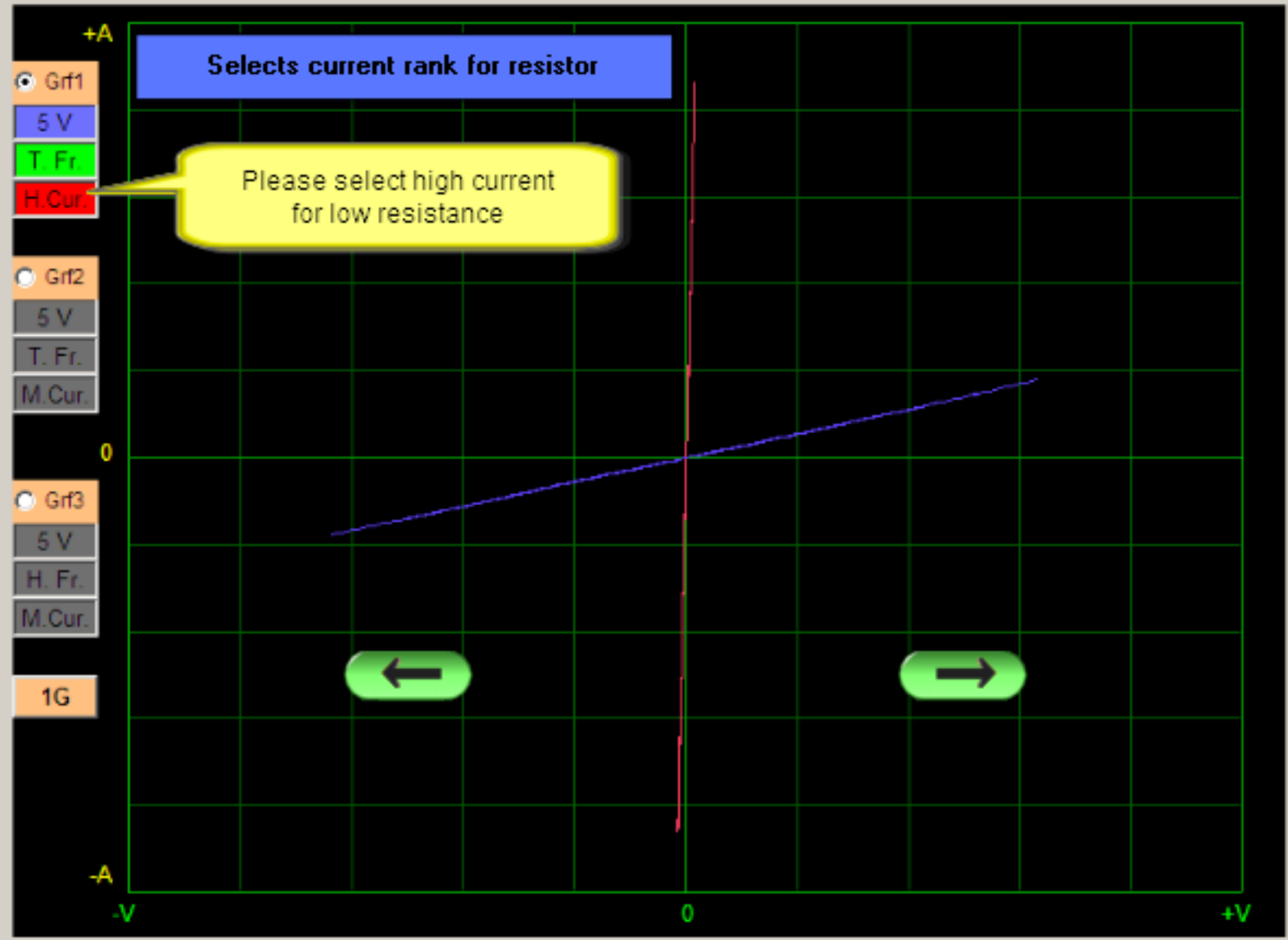
L. Current (47K)  
M. Current (2K7)  
H. Current (550)

Compare  
 Capasite Test  
 T.T.T. FET IGBT

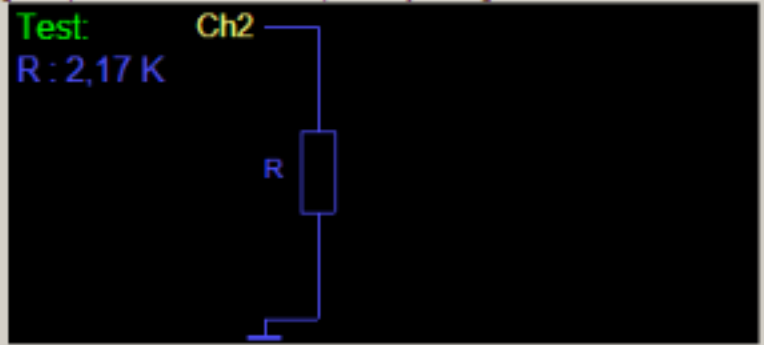
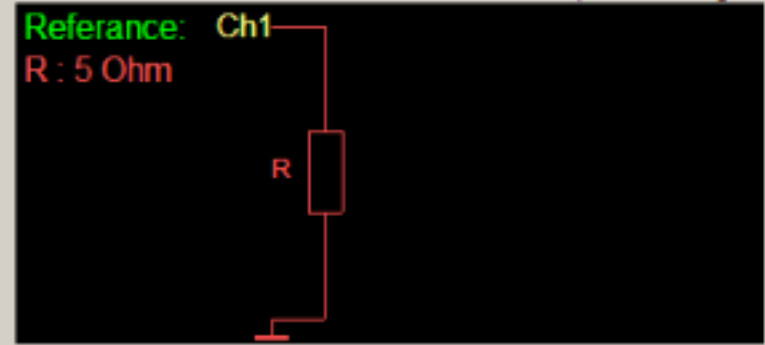
Memory Save - Test

**Recording**

Tolerance (%) **3**



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2 V  
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Test Frk.  
H Frk (5-10V)

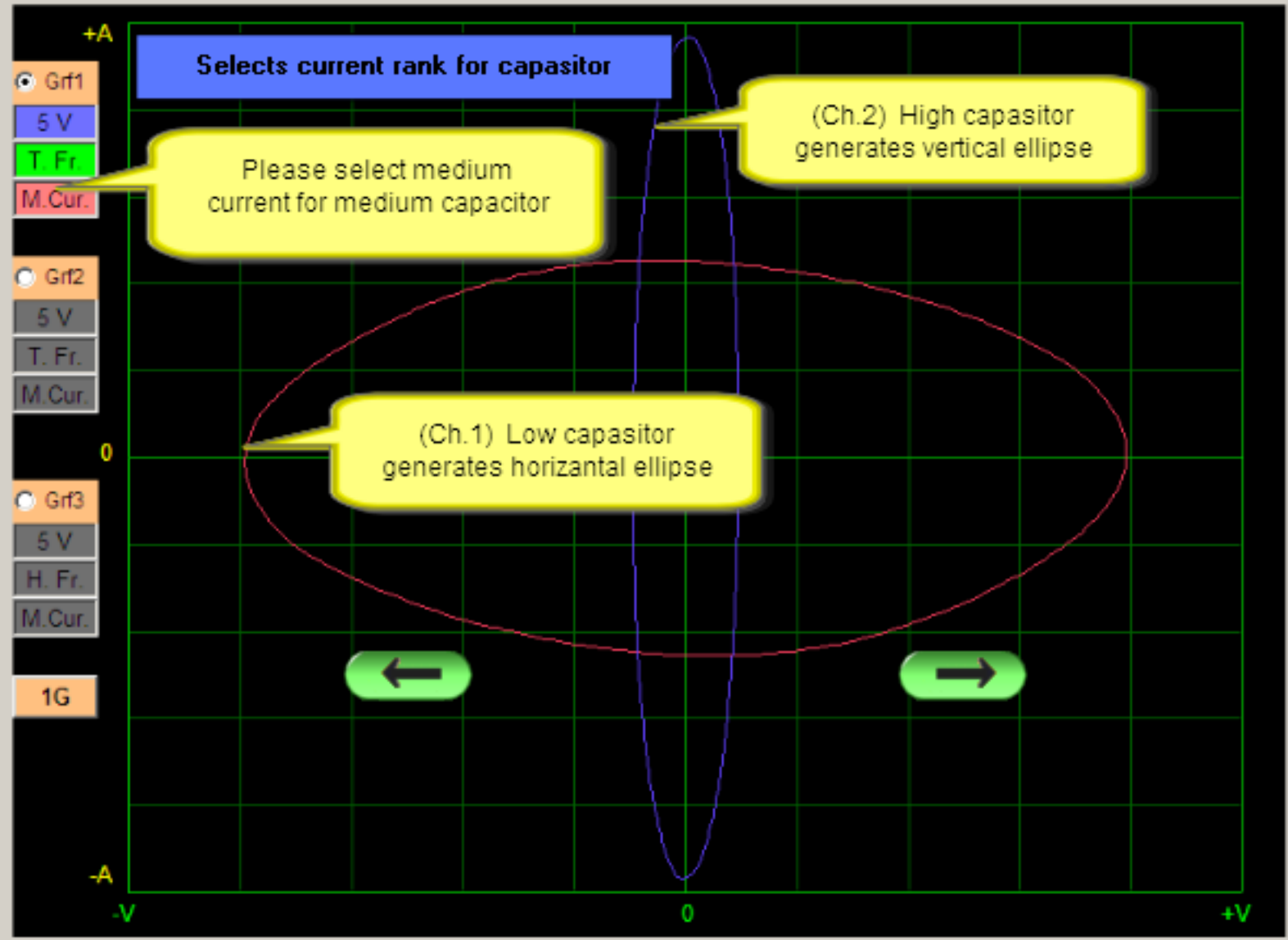
L. Current (47K)  
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H. Current (550)

Compare  
 Capasite Test  
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Memory Save - Test

Recording

Tolerance (%)



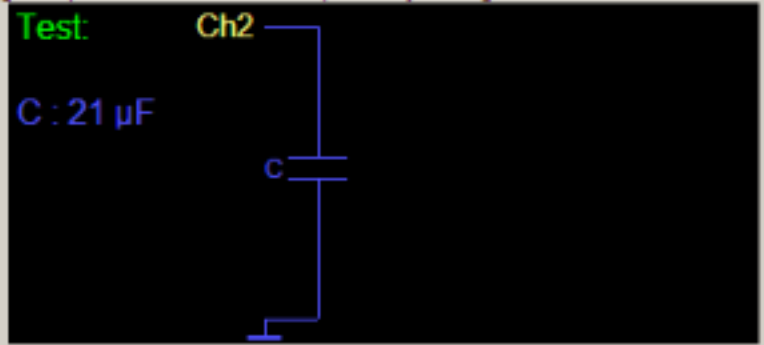
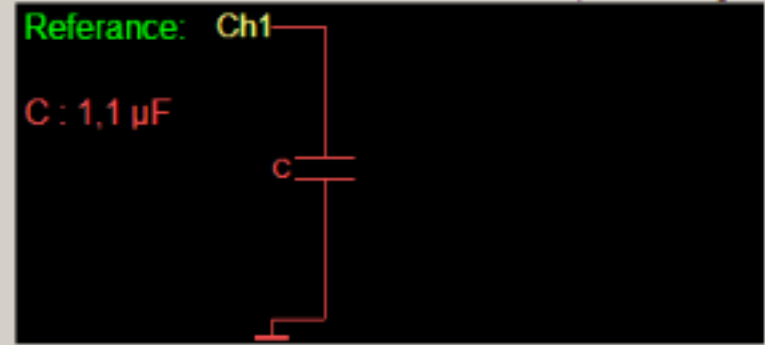
Selects current rank for capacitor

Please select medium current for medium capacitor

(Ch.2) High capacitor generates vertical ellipse

(Ch.1) Low capacitor generates horizontal ellipse

ATTENTION: Probe must be at 1X position. High-voltage capacitors must be emptied by using a resistor.



Test:

Channel 1 - 2

Automatic

1 V  
2 V  
5 V  
10 V

Very Low Frk.  
Low 2 Frk.  
Lov 1 Frk.  
Test Frk.  
H Frk (5-10V)

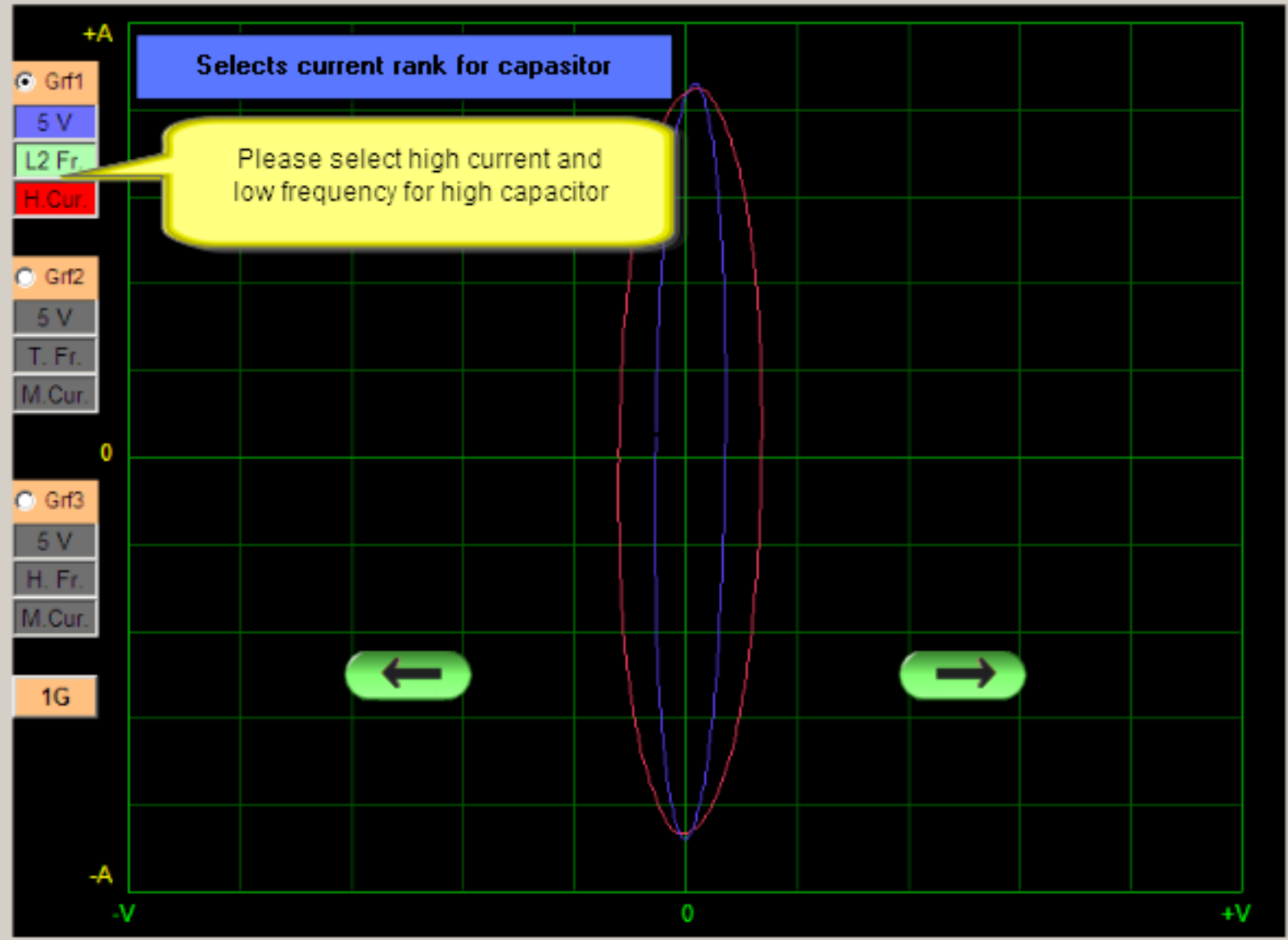
L. Current (47K)  
M. Current (2K7)  
H. Current (550)

Compare  
 Capasite Test  
 T.T.T. FET IGBT

Memory Save - Test

Recording

Tolerance (%)



ATTENTION: Probe must be at 1X position. High-voltage capacitors must be emptied by using a resistor.

Reference: Ch1

C : 442  $\mu$ F

Test: Ch2

C : 935  $\mu$ F

Test:

Channel 1 - 2

Automatic

1 V  
2 V  
5 V  
10 V

Very Low Frk.  
Low 2 Frk.  
Lov 1 Frk.  
Test Frk.  
H Frk (5-10V)

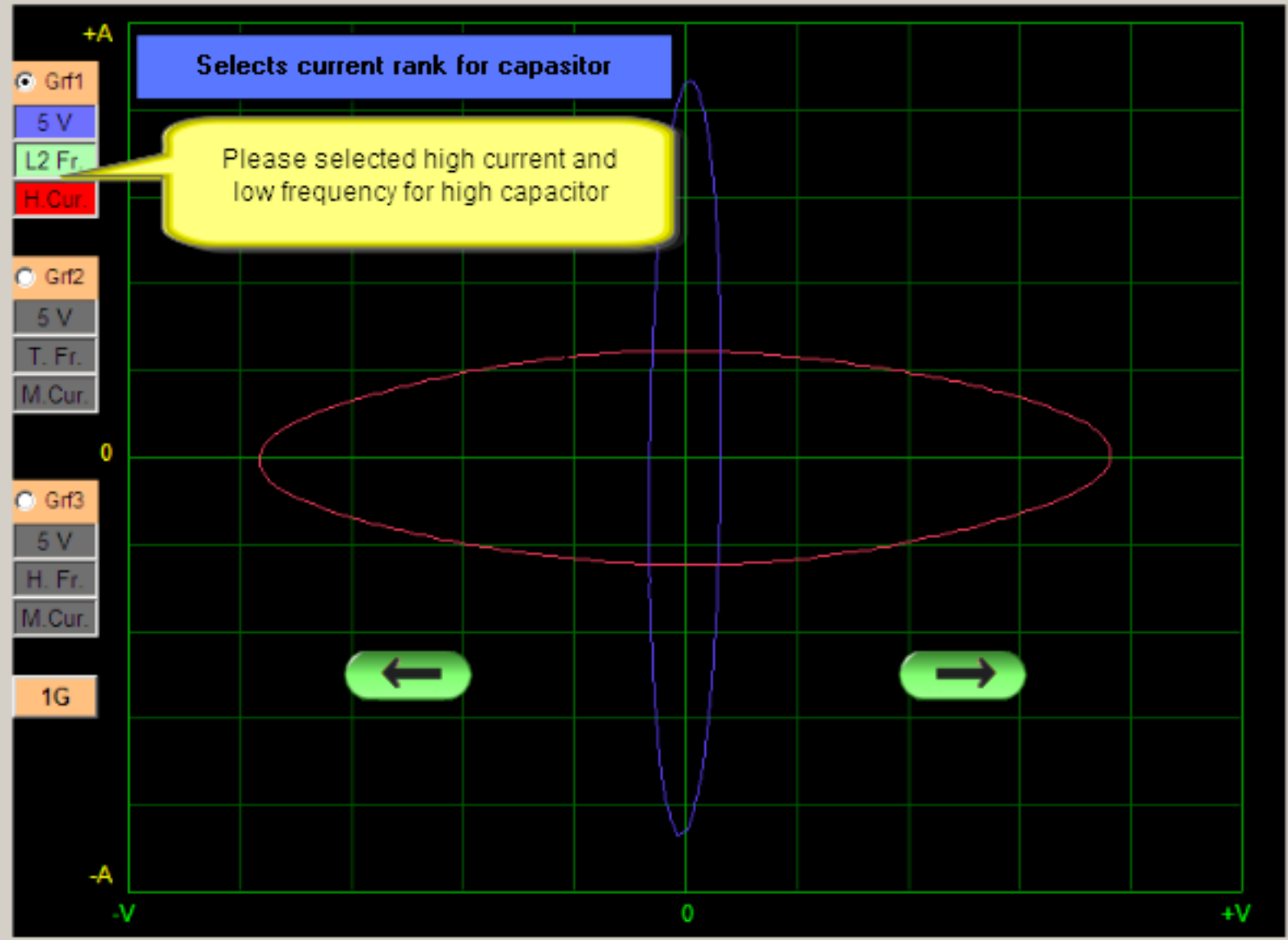
L. Current (47K)  
M. Current (2K7)  
H. Current (550)

Compare  
 Capasite Test  
 T.T.T. FET IGBT

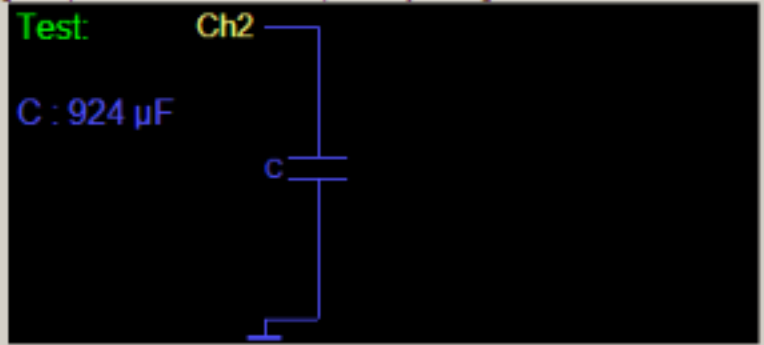
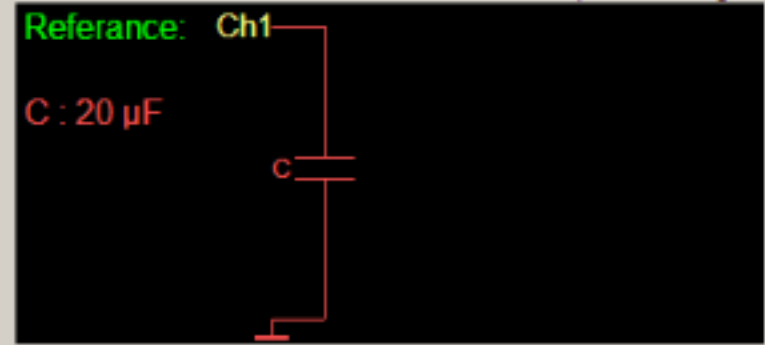
Memory Save - Test

Recording

Tolerance (%)



ATTENTION: Probe must be at 1X position. High-voltage capacitors must be emptied by using a resistor.



Test:

**Channel 1 - 2**

Automatic

1 V  
2 V  
5 V  
10 V

Very Low Frk.  
Low 2 Frk.  
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Test Frk.  
H Frk (5-10V)

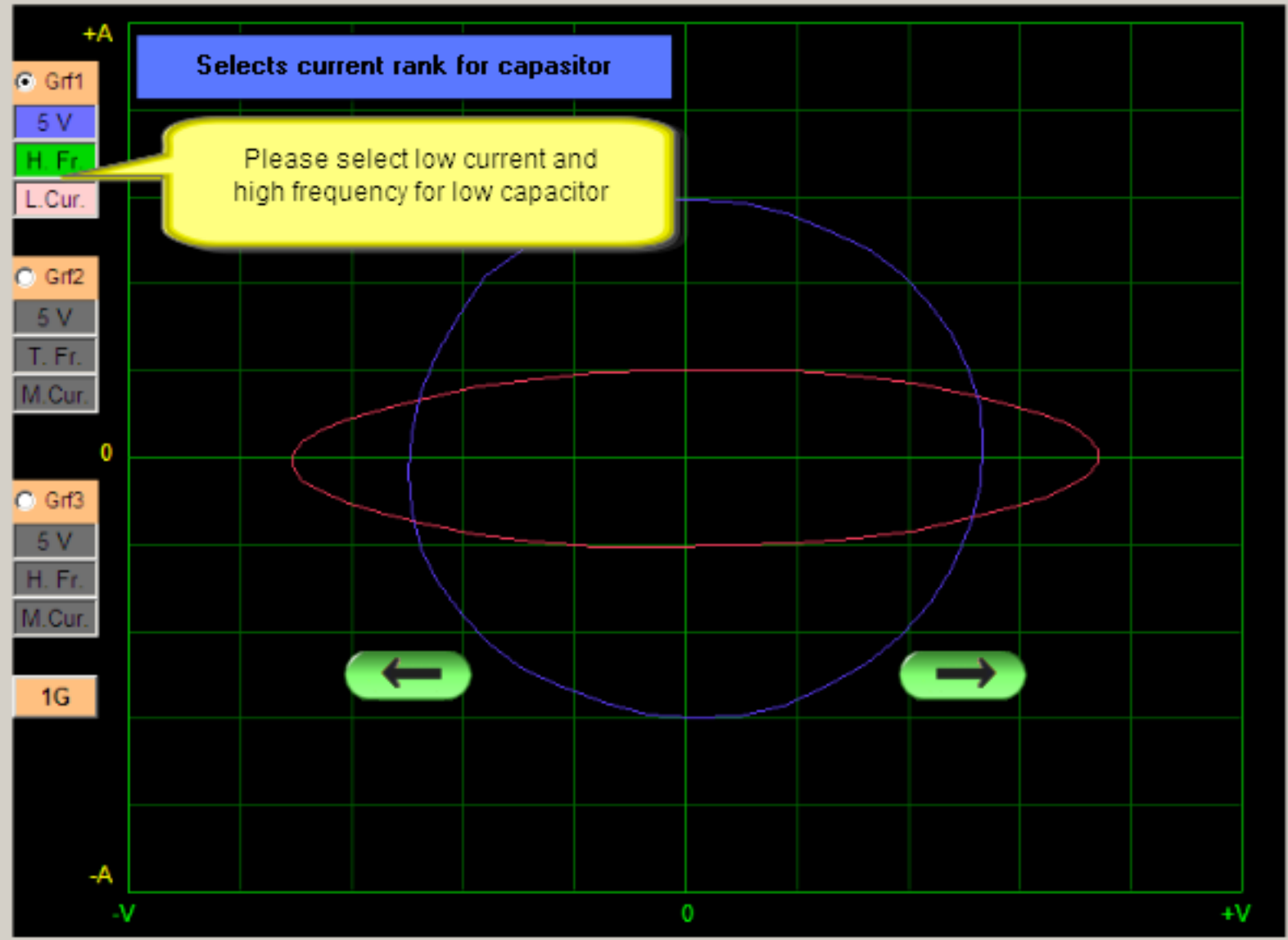
L. Current (47K)  
M. Current (2K7)  
H. Current (550)

Compare  
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 T.T.T. FET IGBT

Memory Save - Test

**Recording**

Tolerance (%) **3**

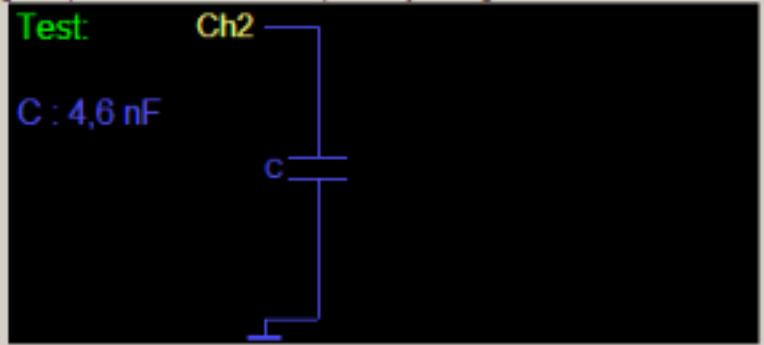
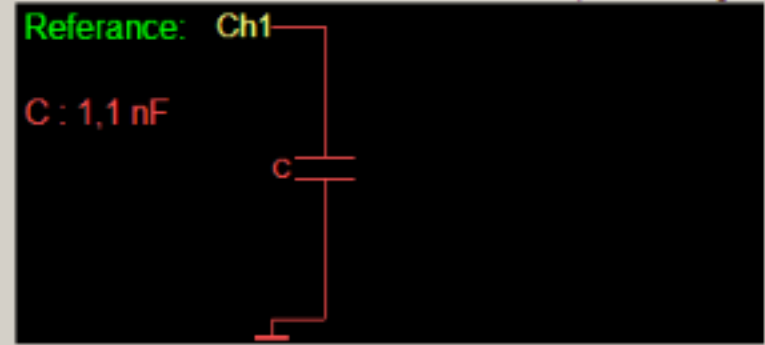


Selects current rank for capacitor

Please select low current and high frequency for low capacitor

- Grf1
  - 5 V
  - H. Fr.
  - L. Cur.
- Grf2
  - 5 V
  - T. Fr.
  - M. Cur.
- Grf3
  - 5 V
  - H. Fr.
  - M. Cur.
- 1G

ATTENTION: Probe must be at 1X position. High-voltage capacitors must be emptied by using a resistor.





Test:

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1 V  
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5 V  
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Test Frk.  
H Frk (5-10V)

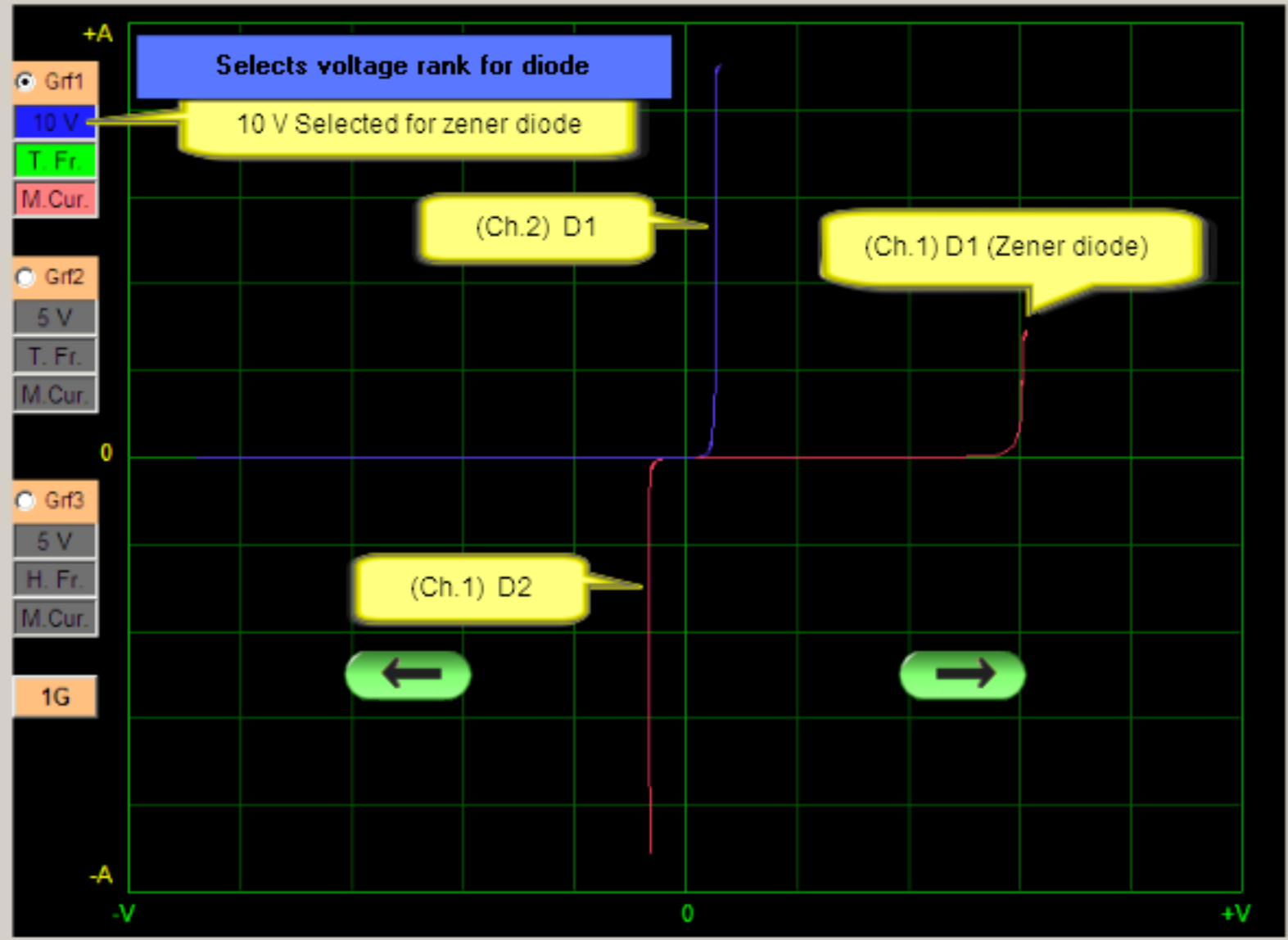
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H. Current (550)

Compare  
 Capasite Test  
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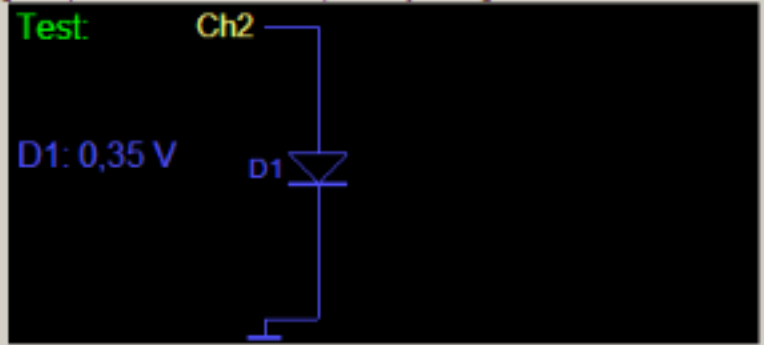
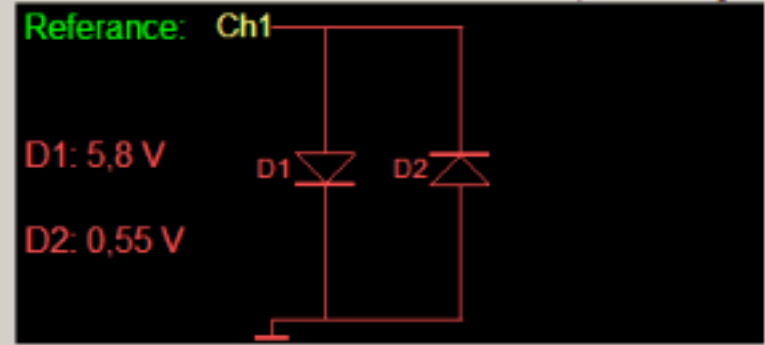
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Recording

Tolerance (%)



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OSCILLOSCOPE - ANALOG OUTPUT

FAULT DETECTOR - VI TESTER

Test:

Channel 1 - 2

Automatic

1 V

2 V

5 V

10 V

Very Low Frk.

Low 2 Frk.

Low 1 Frk.

Test Frk.

H Frk (5-10V)

L. Current (47K)

M. Current (2K7)

H. Current (550)

Compare

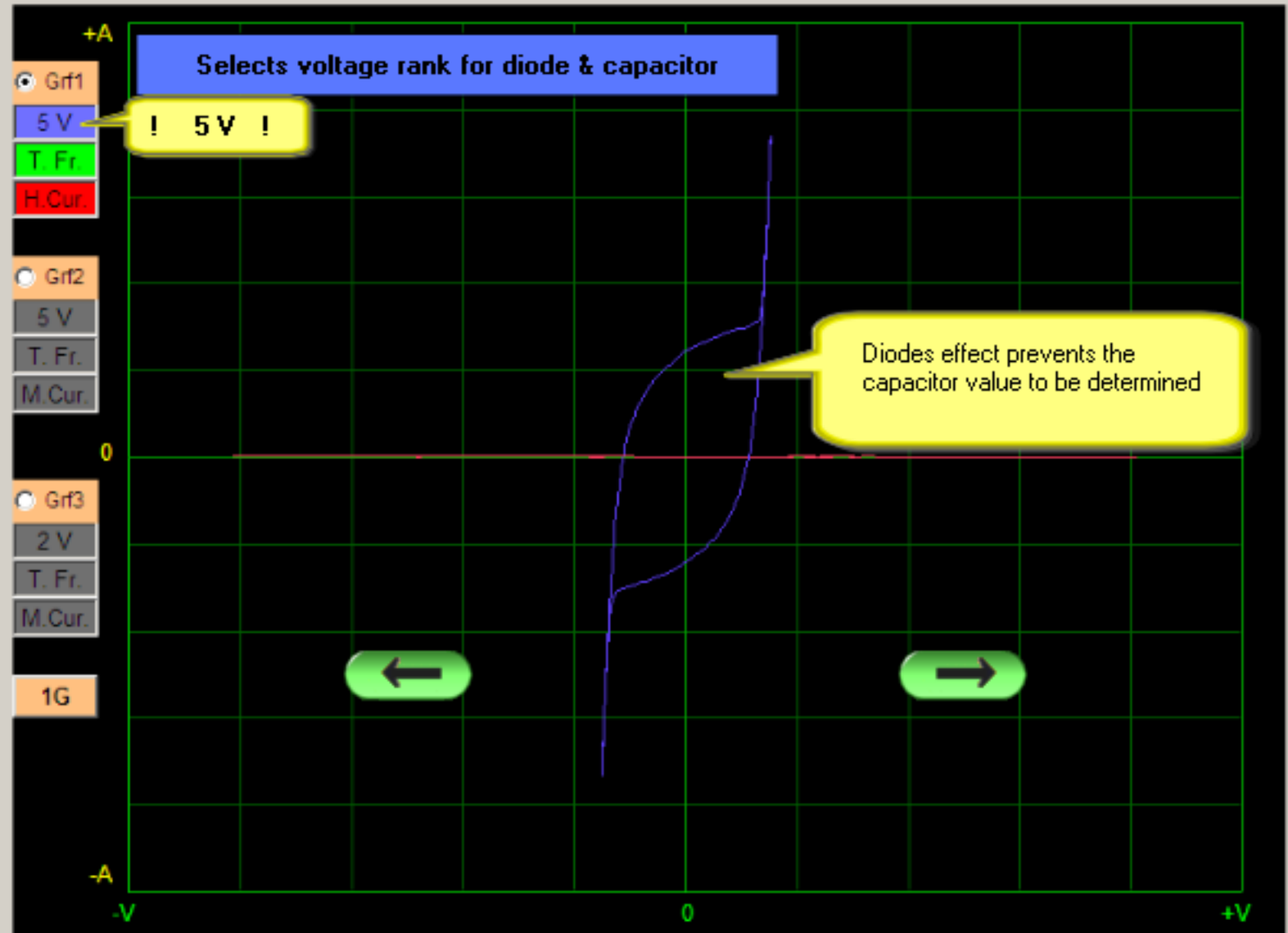
Capasite Test

T.T.T. FET IGBT

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Recording

Tolerance (%)



ATTENTION: Probe must be at 1X position. High-voltage capacitors must be emptied by using a resistor.

Reference: Ch1

Open Circuit

Test: Ch2

D1: 0,7 V

D2: 0,7 V

C

Test:

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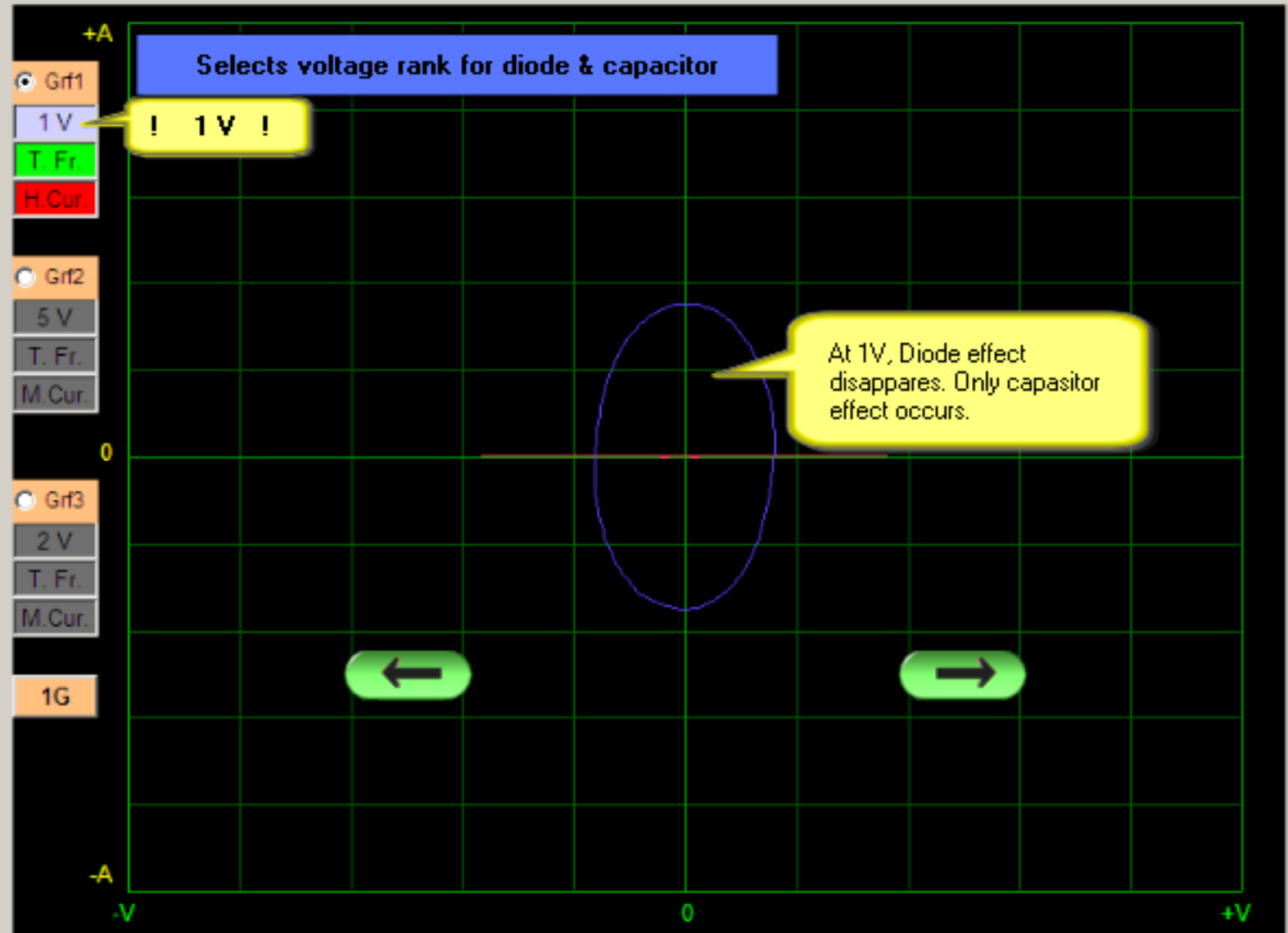
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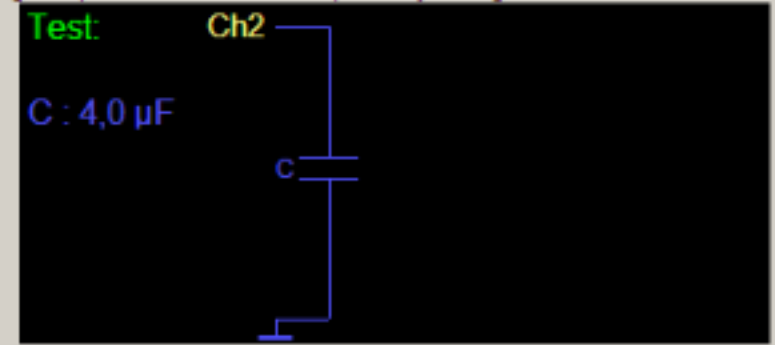
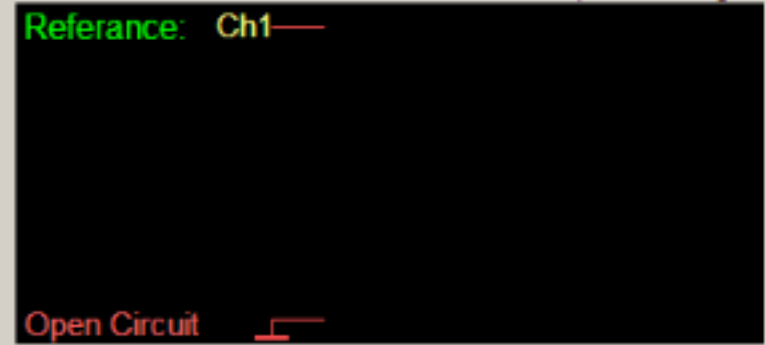
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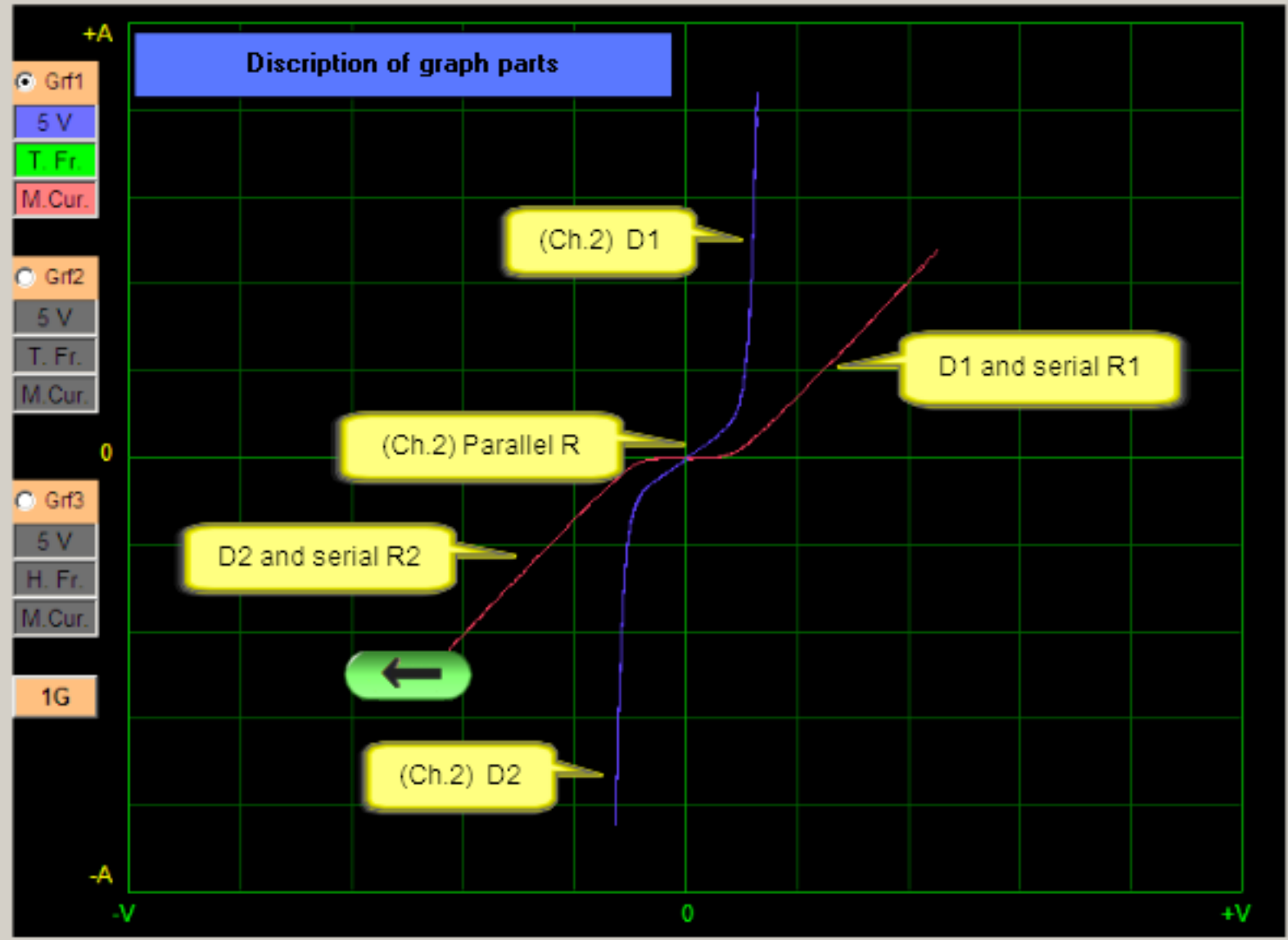
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